

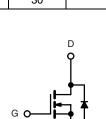
TO-252

D

Top View

# N-Channel 20-V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)		
	0.005 at V <sub>GS</sub> = 10 V	30			
20	0.0057 at V <sub>GS</sub> = 4.5 V	30	15.5 nC		
	0.0076 at V <sub>GS</sub> = 2.5 V	30			





#### **FEATURES**

- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Gen III Power MOSFET
- 100 % R<sub>g</sub> Tested
- 100 % UIS Tested
- Compliant to RoHS Directive 2002/95/EC



#### **APPLICATIONS**

- DC/DC
- Low Voltage Drive
- POL

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	20	V	
Gate-Source Voltage		V <sub>GS</sub>	± 12		
	$T_C = 25 ^{\circ}\text{C}$ $T_C = 70 ^{\circ}\text{C}$		30 <sup>a</sup> 30 <sup>a</sup>		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	22.6 <sup>b, c</sup>		
T <sub>A</sub> = 70 °C		I <sub>DM</sub>	18.2 <sup>b, c</sup>	Α	
Continuous Source-Drain Diode Current	$T_C = 25 ^{\circ}\text{C}$ $T_A = 25 ^{\circ}\text{C}$	I <sub>S</sub>	25 <sup>a</sup> 4.1 <sup>b, c</sup>		
Single Pulse Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	20	1	
Single Pulse Avalanche Energy	L=0.1 mn	E <sub>AS</sub>	20	mJ	
	T <sub>C</sub> = 25 °C		27.7		
Maximum Power Dissipation	$T_C = 70  ^{\circ}C$	P <sub>D</sub>	17.7	w	
Waximum Fower Bloopation	T <sub>A</sub> = 25 °C	. Б	4.6 <sup>b, c</sup>	7 **	
	T <sub>A</sub> = 70 °C		3.0 <sup>b, c</sup>		
Operating Junction and Storage Temperature Ra	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C		
Soldering Recommendations (Peak Temperature		260	7		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient	t ≤ 10 s	R <sub>thJA</sub>	22	27	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R <sub>thJC</sub>	3.5	4.5	O/ <b>VV</b>	

### Notes:

- a. Package limited.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.



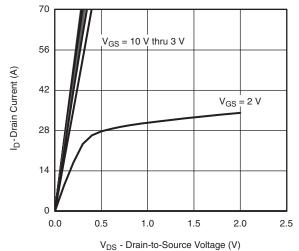
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				<u>'</u>	•		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = 250 μA		19		mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA		- 4.0			
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu A$	0.6		1.5	٧	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 12 \text{ V}$			± 100	nA	
7 0		$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$			1		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			Α	
	, ,	$V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		0.0041	0.005		
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 4.5 \text{ V}, I_D = 8 \text{ A}$		0.0046	0.0057	0057 Ω	
		$V_{GS} = 2.5 \text{ V}, I_D = 6 \text{ A}$		0.0063	0.0076		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 10 A		70		S	
Dynamic <sup>b</sup>					<u> </u>		
Input Capacitance	C <sub>iss</sub>			1785			
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		460		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	D3 - 7 G3 - 7		210		F.	
Theverse transier Capacitance		V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A		32			
Total Gate Charge	$Q_g$	23 - 7 d3 - 7 D -		15.5	23.5	nC	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$		3			
Gate-Drain Charge	Q <sub>gd</sub>	ge r de r b		3.6			
Gate Resistance	R <sub>g</sub>	f = 1 MHz	0.2	0.75	1.5	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			11	22		
Rise Time	t <sub>r</sub>	$V_{DD} = 10 \text{ V}, R_{I} = 10 \Omega$		11	22		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_q = 1 \Omega$		30	55	1	
Fall Time	t <sub>f</sub>	•		9	18	1	
Turn-On Delay Time	t <sub>d(on)</sub>			19	35	ns	
Rise Time	t <sub>r</sub>	$V_{DD} = 10 \text{ V}, R_{I} = 10 \Omega$		14	28		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_q = 1 \Omega$		36	65		
Fall Time	t <sub>f</sub>	g		13	26	•	
<b>Drain-Source Body Diode Characteristic</b>	:s				<u> </u>		
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			25		
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				70	A	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 5 A		0.71	1.1	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			21	40	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			10.5	20	nC	
Reverse Recovery Fall Time		$t_a$ $t_b = 5 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, \text{ fJ} = 25 \text{ C}$		11		<u> </u>	
Reverse Recovery Rise Time	t <sub>b</sub>			10	<del> </del>	ns	

#### Notes:

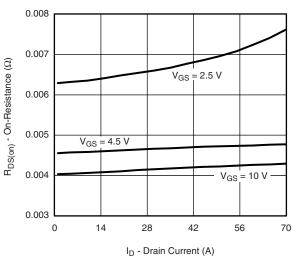
- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

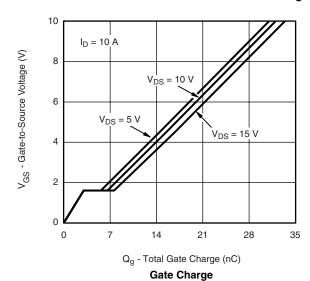




#### **Output Characteristics**

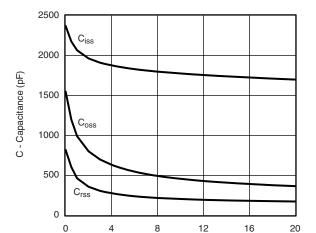


On-Resistance vs. Drain Current and Gate Voltage



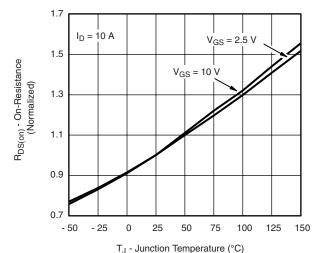
10 8 I<sub>D</sub> - Drain Current (A) T<sub>C,</sub>= 125 °C  $T_C = 25 \, ^{\circ}C$ 2 0.0 0.6 1.2 1.8 2.4 3.0

V<sub>GS</sub> - Gate-to-Source Voltage (V) **Transfer Characteristics** 



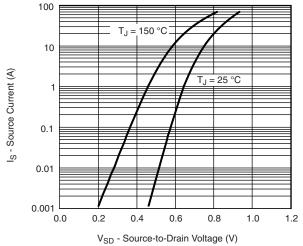
V<sub>DS</sub> - Drain-to-Source Voltage (V)

#### Capacitance

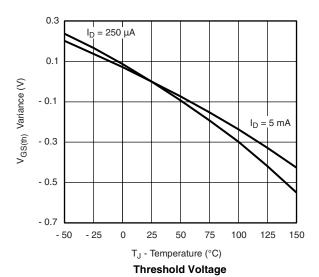


On-Resistance vs. Junction Temperature





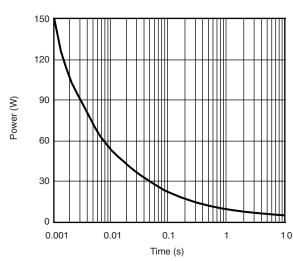
Source-Drain Diode Forward Voltage



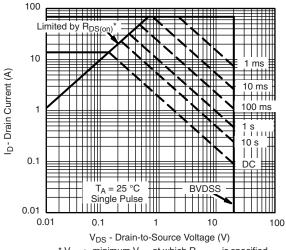
0.025 I<sub>D</sub> = 10 A 0.020  $\mathsf{R}_{\mathsf{DS}(\mathsf{on})}$  - On-Resistance  $(\Omega)$ 0.015 0.010 T<sub>J</sub> = 125 °C 0.005 T<sub>J</sub> = 25 °C 0.000 0 1 2 3 4 5 6 9 10 8

V<sub>GS</sub> - Gate-to-Source Voltage (V)

On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power, Junction-to-Ambient

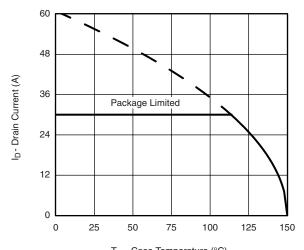


\*  $V_{GS}$  > minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified

Safe Operating Area, Junction-to-Ambient

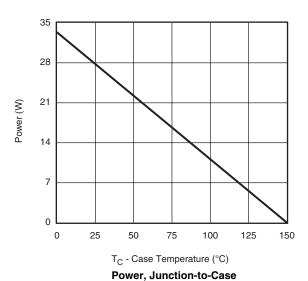


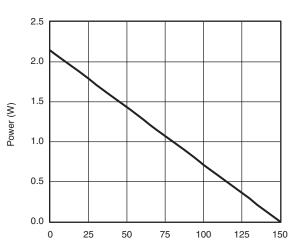




T<sub>C</sub> - Case Temperature (°C)

#### **Current Derating\***



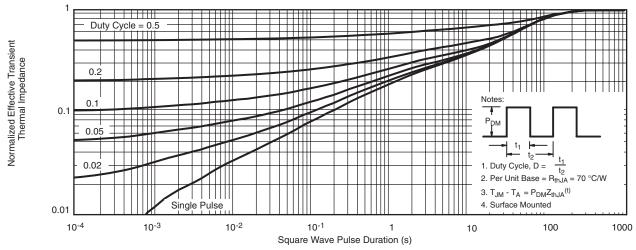


T<sub>A</sub> - Ambient Temperature (°C)

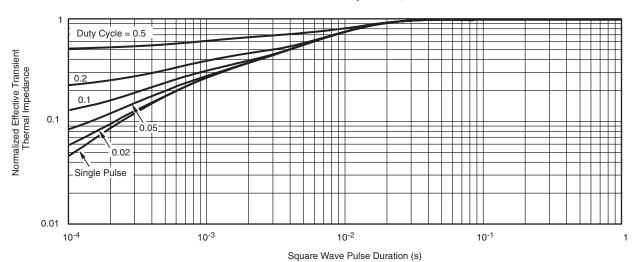
Power, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





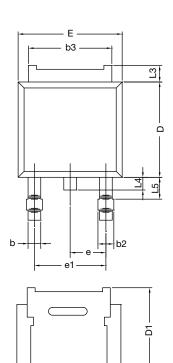
Normalized Thermal Transient Impedance, Junction-to-Ambient



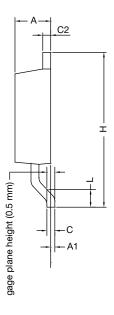
Normalized Thermal Transient Impedance, Junction-to-Case



# **TO-252AA CASE OUTLINE**



E1



	MILLIMETERS		INC	HES		
DIM.	MIN.	MAX.	MIN.	MAX.		
А	2.18	2.38	0.086	0.094		
A1	-	0.127	-	0.005		
b	0.64	0.88	0.025	0.035		
b2	0.76	1.14	0.030	0.045		
b3	4.95	5.46	0.195	0.215		
С	0.46	0.61	0.018	0.024		
C2	0.46	0.89	0.018	0.035		
D	5.97	6.22	0.235	0.245		
D1	5.21	-	0.205	-		
Е	6.35	6.73	0.250	0.265		
E1	4.32	-	0.170	-		
Н	9.40	10.41	0.370	0.410		
е	2.28	2.28 BSC		BSC		
e1	4.56 BSC		0.180 BSC			
L	1.40	1.78	0.055	0.070		
L3	0.89	1.27	0.035	0.050		
L4	-	1.02	-	0.040		
L5	1.14	1.52	0.045	0.060		
ECN: X12-0247-Rev. M, 24-Dec-12						

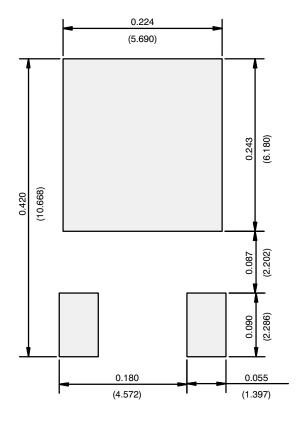
DWG: 5347

#### Note

• Dimension L3 is for reference only.



# **RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)**



Recommended Minimum Pads Dimensions in Inches/(mm)

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